

	9. Marketplace aims to reshape retail. By: Reardon, Marguerite. Information Week, January 24, 2000 Issue 770, p79-79, 1p; (AN IPCA0597614)	Add
•	10. AutoSketch returns with a whole new look. By: Orr, Joel. Windows Sources, March 1, 1998, Vol. 6 Issue 3, p68-68, 1p; (AN IPCA0531228)	Add
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 Rough-fuzzy MLP: modular evolution, rule generation, and evaluation Pal, S.K.; Mitra, S.; Mitra, P.; Knowledge and Data Engineering, IEEE Transactions on Volume 15, Issue 1, Jan.-Feb. 2003 Page(s):14 - 25
IEEE JNL

2. An approach to the evaluation of a diagnostic system with incomplete information

Aguilo, I.; Fiol, G.;

Emerging Technologies and Factory Automation, 1999. Proceedings. ETFA '99. 1999 7th IEEE International Conference on

Volume 2, 18-21 Oct. 1999 Page(s):963 - 969 vol.2

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